

Search Notes

Application/Control No.

10/659,101

Examiner

Randall Chin

Applicant(s)/Patent under
Reexamination

CHAN ET AL.

Art Unit

1744

SEARCHED

Class	Subclass	Date	Examiner
15	143.1	↓	↓
15	167.1	8/1/2005	RC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor name search	8/1/2005	RC